

Model	Tabletop Microscopes TM4000 II	Tabletop Microscopes TM4000Plus II
Magnification	×10 - ×100,000 (Photographic magnification)	
	×25 - ×250,000 (Monitor display magnification)	
Electron source	Pre-centered cartridge tungsten filament	
Accelerating voltage	5 kV, 10 kV, 15 kV, 20 kV	
Image signal	Backscattered electron (BSE)	Secondary electron (SE)
		Backscattered electron (BSE)
		Mix (BSE+ SE)
		UVD-CL
	C.	STEM*
Vacuum mode	Standard Charging reduction	
	Charging reduction Conductor (BSE only)	
Sample stage traverse	X : 40 mm	
	Y : 35 mm	
	T : -15 - 45°*	
	R:360°*	
Maximum sample size	80 mm (in diameter)	
Maximum sample thickness	50 mm	
Signal detector	High-Sensitivity 4-segment BSE detector	
		High-Sensitivity Low-Vacuum SE detector
Analysis system	Energy Dispersive X-ray Spectrometer (EDS)*	
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